

**IGBT** 

TRENCHSTOP™ IGBT3 Chip SIGC15T65E

**Data Sheet** 

Industrial Power Control



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## TRENCHSTOP<sup>™</sup> IGBT3 Chip

#### Features:

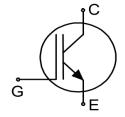
- 650V trench & field stop technology
- Low V<sub>CEsat</sub>
- Low turn-off losses
- Short tail current
- Positive temperature coefficient
- Easy paralleling

#### Recommended for:

Power modules

### **Applications:**

Drives



Chip Type	<b>V</b> <sub>CE</sub>	<b>I</b> Cn	Die Size	Package
SIGC15T65E	650V	30A	3.92mm x 3.88mm	Sawn on foil

#### **Mechanical Parameters**

Weenamean aramet					
Die size		3.92 x 3.88			
Emitter pad size		See chip drawing	$mm^2$		
Gate pad size		0.608 x 1.083			
Area total		15.21			
Silicon thickness		70 μm			
Wafer size		200 mm			
Maximum possible ch	ips per wafer	1806			
Passivation frontside		Photoimide			
Pad metal	3200nm AlSiCu				
Backside metal		Ni Ag – system  To achieve a reliable solder connection it is strongly recommended not to consume the Ni layer completely during production process			
Die bond		Electrically conductive epoxy glue and soft solder			
Wire bond		AI, ≤500μm			
Reject ink dot size		Ø 0.65mm; max. 1.2mm			
Storage environment (<6 months)	for original and sealed MBB bags	Ambient atmosphere air, temperature 17°C – 25°C			
	for open MBB bags	Acc. IEC 62258-3; Section 9.4 Storage Environment.			



#### **Maximum Ratings**

In general, from reliability and lifetime point of view, the lower the operation junction temperature and/or the applied voltage, the greater the expected lifetime of any semiconductor device.

Parameter	Symbol	Value	Unit
Collector-emitter voltage, $T_{vj}$ =25°C	V <sub>CE</sub>	650	V
DC collector current, limited by $T_{\rm vj\;max}^{\;\;1}$	I <sub>C</sub>	-	Α
Pulsed collector current, $t_p$ limited by $T_{\rm vjmax}^{\ \ 2}$	I <sub>C,puls</sub>	90	Α
Gate-emitter voltage	$V_{GE}$	±20	V
Virtual junction temperature	$T_{\rm vj}$	-40 +175	°C
Short circuit data $^{1/2/3}$ $V_{GE}$ =15V, $V_{CC}$ =360V, $T_{vj}$ =150°C	t <sub>sc</sub>	6	μs

### Static Characteristics (tested on wafer), T<sub>vi</sub>=25°C

Parameter	Symbol	Conditions	Value			Unit	
raiailietei	Symbol	Conditions	min.	typ.	max.		
Collector-emitter breakdown voltage	V <sub>(BR)CES</sub>	$V_{\text{GE}}$ =0V, $I_{\text{C}}$ =2mA	650	ı	ı		
Collector-emitter saturation voltage	V <sub>CEsat</sub>	$V_{\rm GE}$ =15V, $I_{\rm C}$ =30A	1.03	1.45	1.87	V	
Gate-emitter threshold voltage	$V_{\rm GE(th)}$	$I_{\rm C}$ =430 $\mu$ A, $V_{\rm GE}$ = $V_{\rm CE}$	5.1	5.8	6.4		
Zero gate voltage collector current	I <sub>CES</sub>	$V_{CE} = 650 \text{V}, \ V_{GE} = 0 \text{V}$	-	-	1.6	μA	
Gate-emitter leakage current	I <sub>GES</sub>	$V_{CE} = 0V, V_{GE} = 20V$	ı	ı	300	nA	
Integrated gate resistor	r <sub>G</sub>			none		Ω	

### **Electrical Characteristics 2**

Parameter	Symbol	Conditions	Value			Unit
raidilletei	Syllibol	Conditions	min.	typ.	max.	Onit
Collector-emitter saturation voltage	$V_{CEsat}$	$V_{\text{GE}}$ =15V, $I_{\text{C}}$ =30A, $T_{\text{vj}}$ =175°C	-	1.9	-	V
Input capacitance	C <sub>ies</sub>	V <sub>CE</sub> =25V,	-	1630	-	nF
Reverse transfer capacitance	C <sub>res</sub>	$V_{GE}$ =0V, $f$ =1MHz $T_{Vj}$ =25°C	-	50	-	pF

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<sup>&</sup>lt;sup>1</sup> Depending on thermal properties of assembly.

<sup>&</sup>lt;sup>2</sup> Not subject to production test - verified by design/characterization.

<sup>&</sup>lt;sup>3</sup> Allowed number of short circuits: <1000; time between short circuits: >1s.



### **Further Electrical Characteristics**

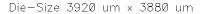
Switching characteristics and thermal properties are depending strongly on module design and mounting technology and can therefore not be specified for a bare die.

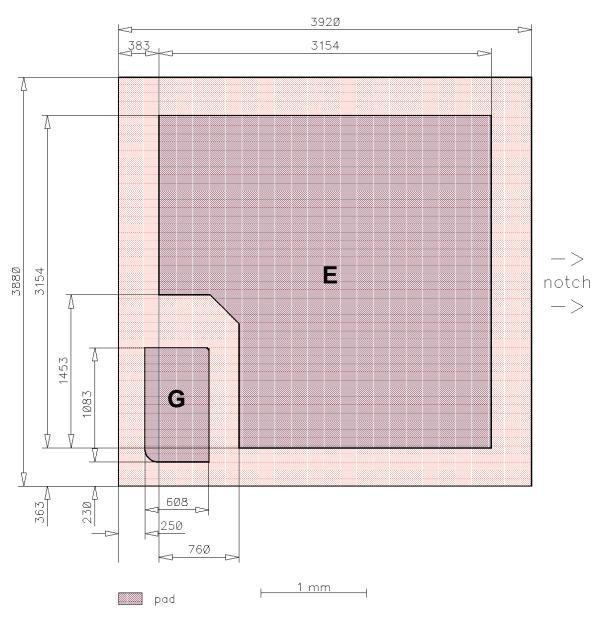
Application example IKW30N60T Rev. 2.6
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### **Chip Drawing**





**E** = Emitter

**G** = Gate



### **Bare Die Product Specifics**

Test coverage at wafer level cannot cover all application conditions. Therefore it is recommended to test all characteristics which are relevant for the application at package level, including RBSOA and SCSOA.

### **Description**

AQL 0.65 for visual inspection according to failure catalogue

Electrostatic Discharge Sensitive Device according to MIL-STD 883

### **Revision History**

Revision	Subjects (major changes since last revision)	Date
2.0	Final data sheet	02.02.2015
2.1	Additional Basic Type, editorial changes	04.11.2016
2.2	Editorial changes	25.01.2017

Relevant App	lication Notes			

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